

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/972,961	CHINO, NAOYOSHI
	Examiner Hai C. Pham	Art Unit 2861

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
347	241, 256	1/20/2006	HP
396	30	1/20/2006	HP
PGPub Text Search		1/20/2006	HP